

10/526097

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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Thomas Mueller Art Unit : Unknown
 Serial No. : N/A Examiner : Unknown
 Filed : Herewith
 Title : METHOD FOR CALIBRATION OF A PHOTODIODE, SEMICONDUCTOR CHIP AND OPERATING METHOD

Commissioner for Patents
 P.O. Box 1450
 Alexandria, VA 22313-1450

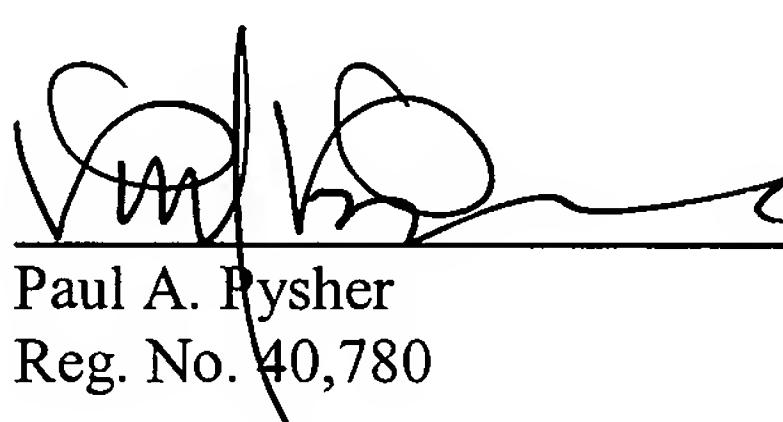
INFORMATION DISCLOSURE STATEMENT

Applicant requests consideration of the references listed on the attached PTO-1449 form. Under 37 C.F.R. § 1.98 (a)(2)(ii), only copies of foreign patent documents and/or non-patent literature are enclosed. Copies of any listed U.S. patents or U.S. patent application publications can be provided upon request.

This statement is being filed with the application. Please apply any charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date: February 25, 2005


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Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 14603-012US1	Application No. 10/7526097
Information Disclosure Statement by Applicant (Use several sheets if necessary)		Applicant Thomas Mueller	
		Filing Date	Group Art Unit
(37 CFR §1.98(b))			

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	4,131,488	12/26/1978	Israel A. Lesk et al.			
	AB	5,844,928	12/01/1998	Kalpendu R. Shastri et al			
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

Foreign Patent Documents or Published Foreign Patent Applications							
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation
							Yes No
	AL	09045744	02/14/97	Japan (Abstract only)			
	AM	05218327	08/27/93	Japan (Abstract only)			
	AN	02105078	04/17/90	Japan (Abstract only)			
	AO	62017621	01/26/87	Japan (Abstract only)			
	AP	62274234	11/28/87	Japan (Abstract only)			
	AQ	WO97/24728	07/10/97	WIPO			
	AR	WO01/86723	11/15/01	WIPO			
	AS	199 62 938	07/19/01	Germany		Abstract	
	AT	29 04 984	05/13/82	Germany		Abstract	

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
	AU	

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	